

Corrosion Reliability of Electronic Devices	
11:00 – 12:40	Room: Galerie A
Chairs	R. Ambat, Technical University of Denmark Lyngby/DK H. Schweigart, Zestron Europe, Ingolstadt/DE
11:00 – 11:20	Corrosion reliability of electronics: prediction, prevention, and control R. Ambat, Technical University of Denmark, Lyngby/DK
11:20 – 11:40	Corrosion prevention by assembly design H. Schweigart, Zestron Europe, Ingolstadt/DE
11:40 – 12:00	Phosphorous based flame retardants for polyamides and corrosion L. Müller ¹ , H. Steffes ² ¹ Robert Bosch GmbH, Reutlingen/DE; ² Bosch Power Tec GmbH, Böblingen/DE
12:00 – 12:20	Effect of iodine on the corrosion of Au-Al wire bond interconnects V. Verdingovas ¹ , L. Müller ² , M. Stendahl Jellesen ¹ , R. Ambat ¹ ¹ Technical University of Denmark, Lyngby/DK; ² Robert Bosch GmbH, Reutlingen/DE
12:20 – 12:40	Cost-efficient feed-throughs with polymers – Interphase design, benchmarking & tightness A. Holm ¹ , J. Jacobsen ¹ , J. Krog ¹ , A. Riis ¹ , J. Harming ¹ , L. Rimestad ¹ ¹ Grundfos Holding A/S, Bjerringbro/DK

12:40 – 14:00	LUNCH BREAK / Room: Exhibition Area
Corrosion Reliability of Electronic Devices	
14:00 – 15:40	Room: Galerie A
Chair	R. Ambat, Technical University of Denmark, Lyngby/DK
14:00 – 14:20	Formation of semiconductive electrochemical migration S. Mattern ¹ , L. Henneken ¹ , M. Nowotnick ² ¹ Robert Bosch GmbH, Schwieberdingen/DE; ² Universität Rostock, Rostock/DE
14:20 – 14:40	Corrosion of printed circuit board assemblies (PCBAs) – Field experience and counter measures J.-H. Klingel, Kunststoff-Chemische Produkte GmbH, Frielzheim/DE
14:40 – 15:00	Contamination, potential bias and humidity effects on electrical performance and corrosion reliability of electronic devices K. Piotrowska ¹ , V. Verdingovas ¹ , M. Stendahl Jellesen ¹ , R. Ambat ¹ ¹ Technical University of Denmark, Lyngby/DK
15:00 – 15:20	Experimental study of humidity distribution inside an electronic enclosure and effect of internal heating H. Conseil ¹ , M. Jellesen ¹ , R. Ambat ¹ ¹ Technical University of Denmark, Lyngby/DK
15:20 – 15:40	Humidity related failure mechanisms and corresponding tests K. Schmidt ¹ , A. Kentved ¹ ¹ DELTA, Hoersholm/DK
15:40 – 16:10	COFFEE BREAK / Room: Exhibition Area
Corrosion Reliability of Electronic Devices	
16:10 – 16:50	Room: Galerie A
Chair	H. Schweigart, Zestron Europe, Ingolstadt/DE
16:10 – 16:30	Thermal effects in electronic systems as an implication of electrochemical corrosion F. Petri, Robert Bosch GmbH, Reutlingen/DE
16:30 – 16:50	Sulphur induced corrosion of electronics M. Jellesen ¹ , V. Verdingovas ¹ , S. Davidsdottir ¹ , R. Ambat ¹ ¹ Technical University of Denmark, Lyngby/DK